

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination ONO ET AL.	
		Examiner C. Melissa Koslow	Art Unit 1793	Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2002/0063301	05-2002	Hanamoto et al.	257/432
*	B US-2004/0041220	03-2004	Kwak et al.	257/432
*	C US-2004/0056990	03-2004	Setiur et al.	349/069
*	D US-7,026,755	04-2006	Setiur et al.	313/501
*	E US-7,239,085	07-2007	Kawamura, Hiroshi	313/582
*	F US-5,714,835	02-1998	Zachau et al.	313/486
*	G US-2003/0085853	05-2003	Shiiki et al.	345/60
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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